

<b>Notice of References Cited</b>	Application/Control No. 09/943,209	Applicant(s)/Patent Under Reexamination LAM ET AL.	
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**NON-PATENT DOCUMENTS**

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	U	Zambelich, K., "Totally Data-driven Automated Testing", copyright 1998, White Paper, < <a href="http://www.dkl.com/pdf/datadriven.pdf">http://www.dkl.com/pdf/datadriven.pdf</a> > or < <a href="http://www.sqa-test.com/w_paper1.html">http://www.sqa-test.com/w_paper1.html</a> >
	V	
	W	
	X	

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